

ABSTRACT

SAMPLING PROBES, SYSTEMS, APPARATUSES, AND METHODS

A sampling system is provided. The sampling system includes a housing. Mounted to the housing is a Hall effect sensor. A probe configured to contact a sample is inserted into the housing. The probe includes an elongated portion and a restorative spring inserted onto the elongated portion of the probe. The restorative spring provides sufficient restorative force to return the probe to a relaxed position. The Hall effect sensor is configured to sense a field strength generated by the proximity of the restorative spring of the probe in the extended position.

Fig. 19A